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## Amendments to the Claims

(Previously presented) A method of depositing a layer over a substrate,
 comprising:

providing a substrate within a high density plasma reaction chamber;

providing heavy-diatomic hydrogen gas within the reaction chamber;

providing at least one compound having a heavy-hydrogen isotope substituent into the reaction chamber;

generating a high density plasma within the reaction chamber; and chemical vapor depositing a layer over the substrate, the layer incorporating at least a portion of the at least one compound.

- 2. (Original) The method of claim 1 wherein the heavy-hydrogen isotope is deuterium.
- 3. (Previously presented) The method of claim 1 wherein the at least one compound is selected from the group consisting of  $SiD_xH_{4-x}$ ,  $Si_2D_yH_{6-y}$ ,  $PD_zH_{3-z}$ ,  $SiCl_2DH$ , and  $SiCl_2D_2$ ,  $SiO_4C_8D_0H_{20-0}$ , where x=1-4, y=1-6, z=1-3 and q=1-20.
- 4. (Original) The method of claim 1 wherein the layer comprises an oxide material.
- 5. (Original) The method of claim 1 wherein the layer is simultaneously deposited and etched during the depositing.

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- 6. (Original) The method of claim 1 wherein the depositing produces a substantially planar surface.
- (Original) The method of claim 1 wherein the at least one compound is 7. comprised by a mixture, the mixture further comprising at least one of O<sub>2</sub> and O<sub>3</sub>.

Claims 8-44 (Cancelled).